FQA11N90 / FQA11N90_F109 N-Channel QFET® MOSFET



FQA11N90 / FQA11N90_F109 N-Channel QFET[®] MOSFET

900 V, 11.4 A, 960 mΩ

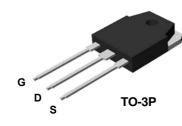
Features

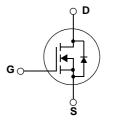
- + 11.4 A, 900 V, $R_{DS(on)}$ = 960 m Ω (Max.) @ V_{GS} = 10 V, ID = 5.7 A
- Low Gate Charge (Typ. 72 nC)
- Low Crss (Typ. 30 pF)
- 100% Avalanche Tested
- RoHS Compliant

Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

April 2013





Absolute Maximum Ratings

| Symbol | Parameter | | Parameter FQA11N90 | | FQA11N90 | Unit | |
|-----------------------------------|--|----------|---|------|----------|------|--|
| V _{DSS} | Drain-Source Voltage | | 900 | V | | | |
| I _D | Drain Current - Continuous ($T_C = 25^{\circ}C$) | | 11.4 | А | | | |
| | - Continuous (T _C = 100°C) | | 7.2 | А | | | |
| I _{DM} | Drain Current - Pulsed | (Note 1) | 45.6 | А | | | |
| V _{GSS} | Gate-Source Voltage | | ± 30 | V | | | |
| E _{AS} | Single Pulsed Avalanche Energy (Note 2) | | Single Pulsed Avalanche Energy (Note 2) | 1000 | mJ | | |
| I _{AR} | Avalanche Current | (Note 1) | 11.4 | А | | | |
| E _{AR} | Repetitive Avalanche Energy | (Note 1) | 30 | mJ | | | |
| dv/dt | Peak Diode Recovery dv/dt | (Note 3) | 4.0 | V/ns | | | |
| P _D | Power Dissipation (T _C = 25°C) | | 300 | W | | | |
| | - Derate above 25°C | | 2.38 | W/°C | | | |
| T _J , T _{STG} | Operating and Storage Temperature Range | | -55 to +150 | °C | | | |
| TL | Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds | | 300 | °C | | | |

Thermal Characteristics

| Symbol | Parameter | FQA11N90 | Unit | |
|---------------------|---|----------|------|--|
| $R_{	ext{	heta}JC}$ | Thermal Resistance, Junction-to-Case, Max. | 0.42 | °C/W | |
| $R_{\theta CS}$ | Thermal Resistance, Case-to-Sink, Typ. | 0.24 | °C/W | |
| $R_{	heta JA}$ | Thermal Resistance, Junction-to-Ambient, Max. | 40 | °C/W | |

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Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|---------------|---------|-----------|------------|----------|
| FQA11N90 | FQA11N90 | TO-3P | | | 30 |
| FQA11N90 | FQA11N90_F109 | TO-3PN | | | 30 |

Electrical Characteristics T_c = 25°C unless otherwise noted

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Unit |
|--|---|---|-----|------|------|------|
| Off Charac | teristics | | | 1 | ļ | 1 |
| BV _{DSS} | Drain-Source Breakdown Voltage | V _{GS} = 0 V, I _D = 250 μA | 900 | | | V |
| $\Delta BV_{DSS}/\Delta T_J$ | Breakdown Voltage Temperature Coefficient | I_D = 250 µA, Referenced to 25°C | | 1.0 | | V/°C |
| I _{DSS} | Zero Gate Voltage Drain Current | V _{DS} = 900 V, V _{GS} = 0 V | | | 10 | μA |
| | | V _{DS} = 720 V, T _C = 125°C | | | 100 | μA |
| I _{GSSF} | Gate-Body Leakage Current, Forward | V _{GS} = 30 V, V _{DS} = 0 V | | | 100 | nA |
| I _{GSSR} | Gate-Body Leakage Current, Reverse | V_{GS} = -30 V, V_{DS} = 0 V | - | | -100 | nA |
| On Charact | teristics | | | | | 1 |
| V _{GS(th)} | Gate Threshold Voltage | $V_{DS} = V_{GS}, I_D = 250 \ \mu A$ | 3.0 | | 5.0 | V |
| R _{DS(on)} | Static Drain-Source On-Resistance | V _{GS} = 10 V, I _D = 5.7 A | - | 0.75 | 0.96 | Ω |
| 9 _{FS} | Forward Transconductance | $V_{DS} = 50 \text{ V}, I_D = 5.7 \text{ A}$ (Note 4) | | 12 | | S |
| Dynamic Cl | haracteristics | | | | | |
| C _{iss} | Input Capacitance | V _{DS} = 25 V, V _{GS} = 0 V, | | 2700 | 3500 | pF |
| C _{oss} | Output Capacitance | f = 1.0 MHz | | 260 | 340 | pF |
| C _{rss} | Reverse Transfer Capacitance | | | 30 | 40 | pF |
| Switching C | Characteristics | | | | | |
| t _{d(on)} | Turn-On Delay Time | V _{DD} = 450 V, I _D = 11.4A, | | 65 | 140 | ns |
| t _r | Turn-On Rise Time | R _G = 25 Ω | | 135 | 280 | ns |
| t _{d(off)} | Turn-Off Delay Time | | | 165 | 340 | ns |
| t _f | Turn-Off Fall Time | - (Note 4, 5) | | 90 | 190 | ns |
| Qg | Total Gate Charge | V _{DS} = 720 V, I _D = 11.4A, | | 72 | 94 | nC |
| Q _{gs} | Gate-Source Charge | V _{GS} = 10 V | | 16 | | nC |
| Q _{gd} | Gate-Drain Charge | (Note 4, 5) | | 35 | | nC |
| Drain-Sour | Let Diode Characteristics and Maximum Ratings | l i | | | | |
| I _S Maximum Continuous Drain-Source Diode Forward Current | | | | | 11.4 | Α |
| I _{SM} | Maximum Pulsed Drain-Source Diode Forward Current | | | | 45.6 | Α |
| V _{SD} | Drain-Source Diode Forward Voltage | V _{GS} = 0 V, I _S =11.4 A | | | 1.4 | V |
| t _{rr} | Reverse Recovery Time | V _{GS} = 0 V, I _S = 11.4 A, | | 850 | | ns |
| Q _{rr} | Reverse Recovery Charge | $dI_{\rm F} / dt = 100 \text{ A}/\mu \text{s}$ (Note 4) | | 11.2 | | μC |

NOTES:

1. Repetitive Rating : Pulse width limited by maximum junction temperature

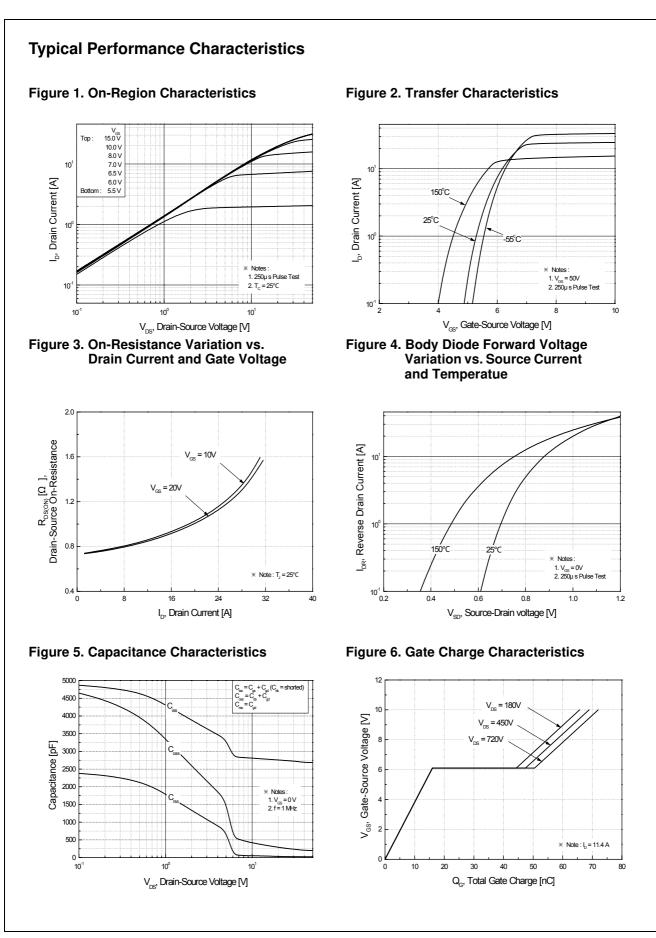
2. L = 15mH, I_{AS} =11.4A, V_DD = 50V, R_G = 25 $\Omega,$ Starting $\mbox{ T}_{J}$ = 25°C

3. I_{SD} \leq 11.4A, di/dt \leq 200A/µs, V_{DD} \leq BV_{DSS,} Starting ~T_J = 25°C

4. Pulse Test : Pulse width $\leq 300 \mu s,$ Duty cycle $\leq 2\%$

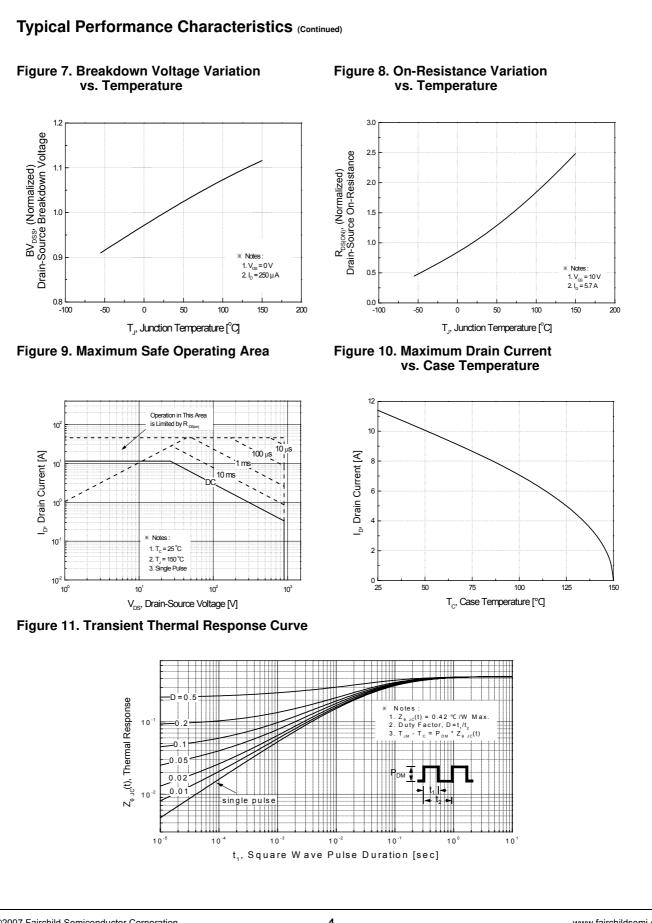
5. Essentially independent of operating temperature

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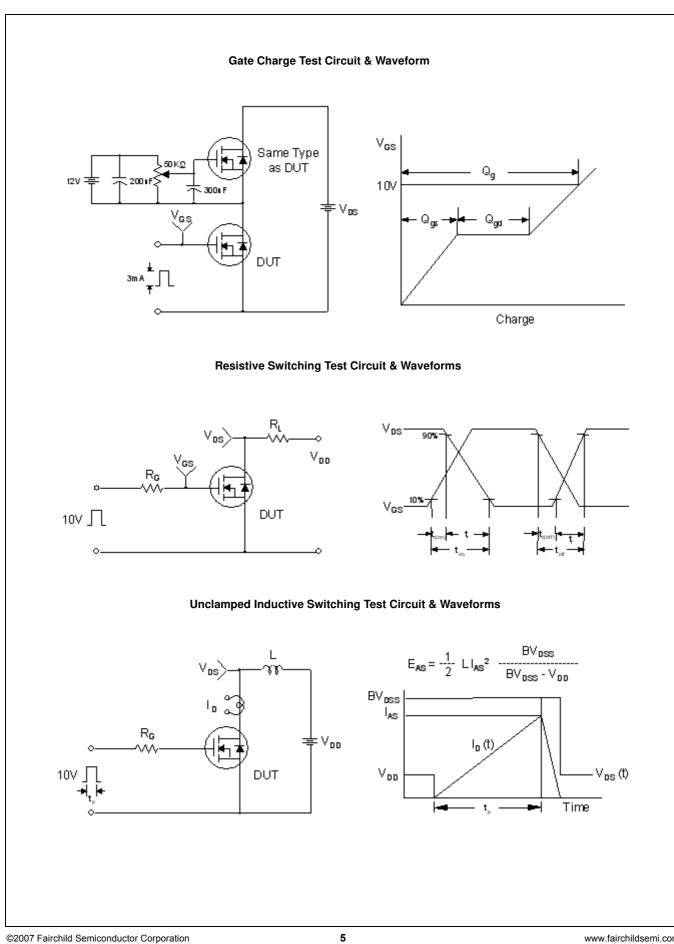


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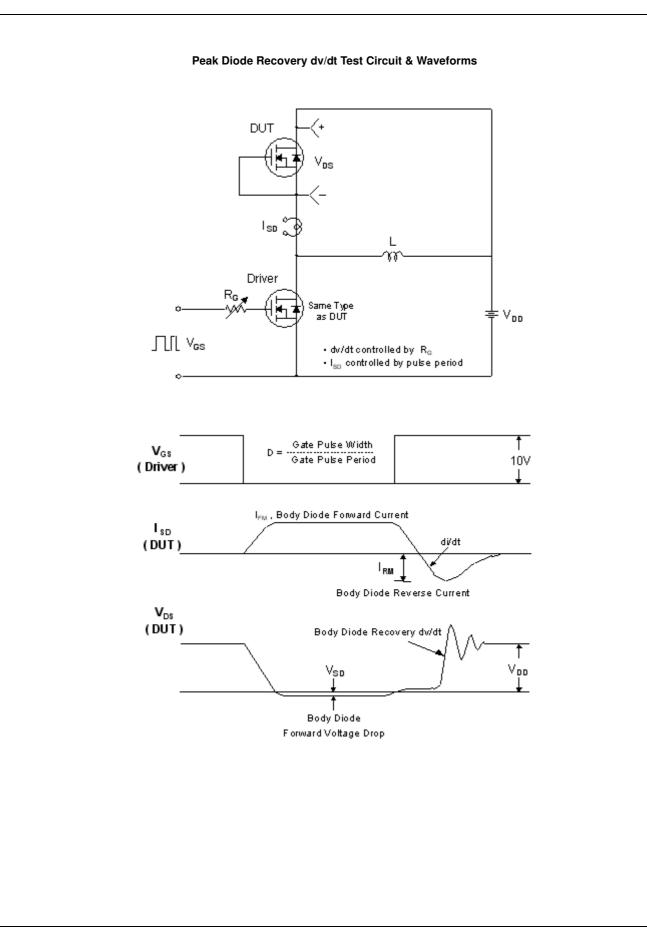
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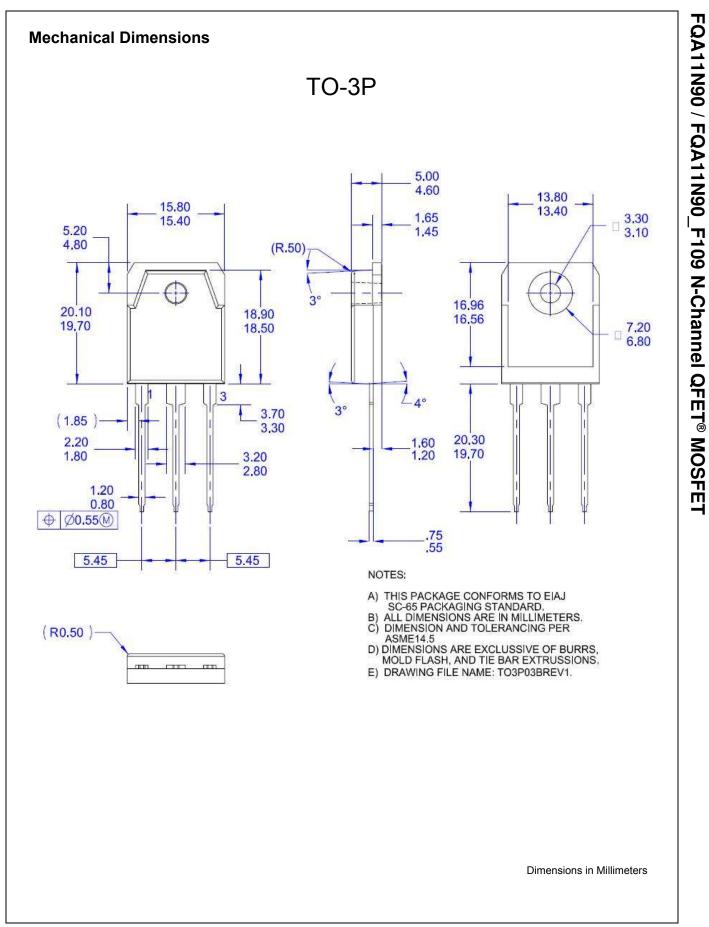


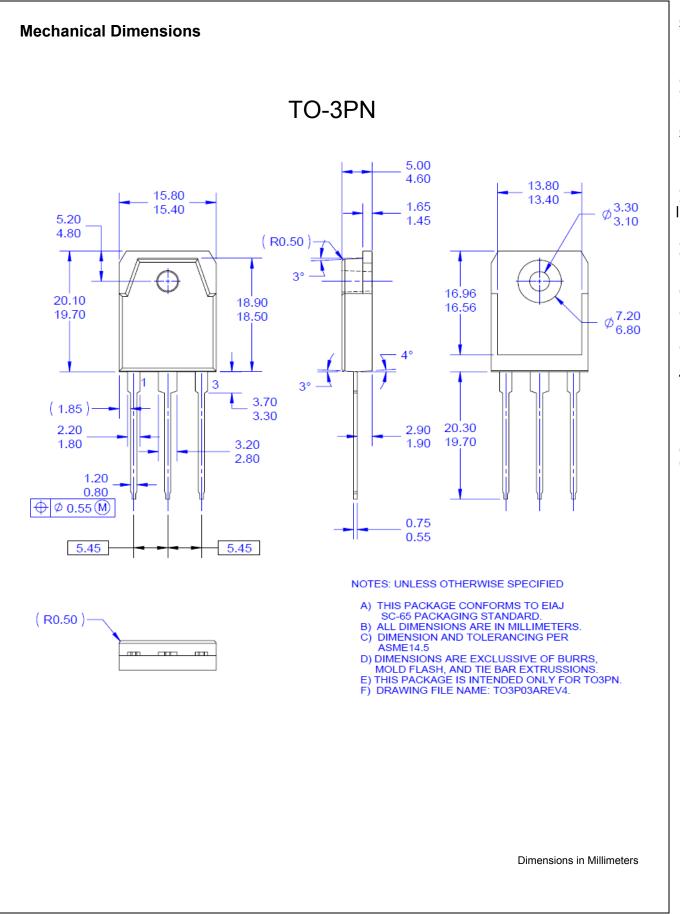
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